

Notice of References Cited

Application/Control No.

10/675,699

Applicant(s)/Patent Under
Reexamination
KENDIG ET AL.

Examiner

ALEX NOGUEROLA

Art Unit

1753

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	CAPLUS abstract of Schiavon et al. ("Solid-state cell for the voltammetric determination of trace electroactive ionic species preconcentrated from highly resistive media at electrodes modified by ion-exchange coatings," Analytic Chimica Acta (1992), 264(2) 221-8)
	V	CAPLUS abstract of Schiavon et al. ("Amperometric monitoring of sulfur dioxide in low-conductive liquid and air samples by electrodes supported on ion-exchange membranes," Analyst (1991), 116(8), 797-801)
	W	Schiavon et al. ("Electrodes supported on ion-exchange membranes as sensors in gases and low-conductivity solvents," Analytica Chimica Acta (1989), 221(1), 27-41)
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.